## Notice of References Cited Application/Control No. 10/810,209 Examiner Anita K. Alanko Applicant(s)/Patent Under Reexamination GOTKIS, YEHIEL Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2005/0042975 A1	02-2005	David, Jeffrey Drue	451/005
	В	US-2005/0046874 A1	03-2005	Caton et al.	356/630
	С	US-6,608,495 B2	08-2003	Sarfaty et al.	324/752
	D	US-5,511,005 A	04-1996	Abbe et al.	702/84
	E	US-6,808,590 B1	10-2004	Gotkis et al.	156/345.16
	F	US-6,629,883	10-2003	Katsuoka et al.	451/332
	G	US-2005/0173259 A1	08-2005	Mavliev et al.	205/645
	Н	US-5,262,726 A	11-1993	Kohmura et al.	324/232
	_	US-6,558,229 B2	05-2003	Kimura et al.	451/8
	J	US-2005/0121141 A1	06-2005	Manens, Antoine P.	156/345.15
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 402527 A2	12-1990	European Patent	CLAREN et al.	G01B 07/10
	0					
	Р					
	Q					
	R					
	s	<b>(</b> *)				
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	·
	٧	
	W	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.